

Title of Change:	Transfer front end manufacturing of AS0149 to TSMC Fab 14 and transition to Rev 1.1			
Proposed Changed Material First Ship Date:	01 Jul 2023 or earlier if approved by customer			
Current Material Last Order Date:	09 Jan 2023 Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.			
Current Material Last Delivery Date:	30 Jun 2023 The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory			
Product Category:	Active components – Integrated circuits			
Contact information:	Contact your local onsemi Sales Office or Mike.Webster@onsemi.com			
PCN Samples Contact:	Contact your local onsemi Sales Office to place sample order. Sample requests are to be submitted no later than 45 days after publication of this change notification. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.			
Additional Reliability Data:	Contact your local onsemi Sales Office or Mike.Webster@onsemi.com			
Type of Notification:	This is an Initial Product/Process Change Notification (IPCN) sent to customers. An IPCN is an advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan. The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN). This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 6 months prior to implementation of the change. In case of questions, contact < <u>PCN.Support@onsemi.com</u> >.			
Change Category				
Category	Type of Change			

Description and Purpose:

Process - Wafer Production

onsemi currently manufactures the Rev 1.0 AS0149 front-end CMOS process at the TSMC Fab 12 facility; once product completes this process in Fab 12, it is then delivered to TSMC Fab 14 for the backside Imager process. Both Fab 12 and Fab 14 are located in Taiwan, but at separate locations.

Move of all or part of wafer fab to a different location/site/subcontractor

As part of the overall capacity improvement strategy at TSMC, we are moving all manufacturing out of FAB 12 and into FAB 14. We are qualifying AS0149 Rev 1.1 products front-end CMOS processing at the TSMC Fab 14 facility to allow us to transfer manufacturing to the FAB 14 facility. The new TSMC Fab 14 facility is fully automotive certified and is currently running the same generation of product/process for *onsemi*. These facilities use the same equipment and manufacturing processes. There are no product material changes as a result of this change. Wafer probe, final test and AEC-Q100 reliability testing is currently being performed on AS0149 REV 1.1 to show equivalence between these facilities.

The AS0149 Revision 1.1 has been released to production at TSMC Fab 12 as a direct replacement for previous AS0149 revisions. The Rev 1.1 has the same functionality as the previous Revision 1.0, but contains a metal layer design change to address:

1) High startup current. Some registers, used for diagnostic purposes only, were in an unknown state at startup. These registers persisted in their unknown state until the part would enter streaming, at which time all register values are reset to their intended values

The Rev1.1 fix was to tie these diagnostic registers to ground. With these registers tied off, there is no path to ground. Validation tests done on Rev1.1 show that the fix has worked. These diagnostic registers are for test purposes only and are not for customer usage. Thus, there are no settings changes required for the customer.



2) DNSU shutter jump. The Rev1.0 design was missing the logic that tied shutter to TX pulsing. The Rev1.1 fix was to insert the missing logic that ties shutter to TX pulsing. This was a metal-only design fix.

There is no change to Form, Fit or Function for this revision. Revision 1.1 is fully backward compatible to Rev 1.0 devices and has been fully qualified at TSMC Fab 12.

The AS0149ATSC00XUEA0-DPBR product discontinuance notice has been distributed and a PDN will be distribued for AS0149ATSC00XUEA0-TRBR next.

This PCN will couple the FAB transfer and the Revision update in a single change.

				From	То	
Fab Site of Front End Processing		TSM	TSMC FAB 12		TSMC FAB 14	
Product Revision		Revision 1.0		Revisio	Revision 1.1	
				From	Тс	0
Product marking change		HBDLR		HBD	HBDMP	
ason / Motivation for Change: Capacity imp		Capacity improve	ement			
nticipated impact on fit, form, Inction, reliability, product Infety or manufacturability:		e qualified and validated based on the same Product Specification. mpacts.				
es Affected:						
nsemi Sites			External Foundry/Subcon Sites			
ne			TSMC Semiconductor, Taiwan			
-	<pre>/ Traceability of</pre>	New OPN associa	ated with the	revision change		
ange: liability Data S DEVICE NAME :	ummary: AS0149ATSC00XUE	New OPN associa	ated with the	revision change		
iability Data S	ummary: AS0149ATSC00XUE mm iBGA	A0-DPBR	ated with the		ndition	Interval
iability Data S DEVICE NAME : CKAGE : 8mmx9	ummary: AS0149ATSC00XUE	A0-DPBR	ated with the	Ca	n dition 100 % max rated Vcc	Interval
ange: liability Data S DEVICE NAME : CKAGE : 8mmx9 Test	ummary: AS0149ATSC00XUE mm iBGA Specific	AO-DPBR ation A108	ated with the	Co Co Co		
ange: liability Data Si DEVICE NAME : CKAGE : 8mmx91 Test HTOL	ummary: AS0149ATSC00XUE mm iBGA Specific JESD22-	A0-DPBR ation A108 0-008	ated with the	Со Та= <u>125</u> ℃Тј, Та	100 % max rated Vcc	1008 hrs
iability Data Si DEVICE NAME : CKAGE : 8mmx9i Test HTOL ELFR	ummary: AS0149ATSC00XUE mm iBGA Specific JESD22- AEC Q10	A0-DPBR ation A108 0-008 ESD-A113	ated with the	Co Ta= <u>125</u> ℃ Tj, Ta MSL	100 % max rated Vcc = <u>125</u> °C	1008 hrs
ange: liability Data St DEVICE NAME : CKAGE : 8mmx9 Test HTOL ELFR PC	ummary: AS0149ATSC00XUE mm iBGA <u>Specific</u> JESD22- AEC Q10 J-STD-020 J	A0-DPBR ation A108 0-008 ESD-A113 A103	ated with the	Co Ta= <u>125</u> °C Tj, Ta MSL Ta	100 % max rated Vcc = <u>125</u> °C 3 @ 260 °C	1008 hrs 24 hrs
ange: iability Data Sub- DEVICE NAME : CKAGE : 8mmx91 Test HTOL ELFR PC HTSL	ummary: AS0149ATSC00XUE mm iBGA JESD22- AEC Q10 J-STD-020 J JESD22-	A0-DPBR ation A108 0-008 ESD-A113 A103 A104	ated with the	Co Ta= <u>125</u> °C Tj, Ta MSL Ta Ta= <u>-55</u>	100 % max rated Vcc = <u>125</u> °C 3 @ 260 °C = <u>150</u> °C	1008 hrs 24 hrs 1008 hrs
iability Data Si DEVICE NAME : CKAGE : 8mmx91 Test HTOL ELFR PC HTSL TC	ummary: AS0149ATSC00XUE mm iBGA JESD22- AEC Q10 J-STD-020 J JESD22- JESD22-	A0-DPBR ation A108 0-008 ESD-A113 A103 A104 A110	ated with the	Co Ta= <u>125</u> °C Tj, Ta MSL Ta Ta= <u>-55</u> 110°C, 85	100 % max rated Vcc = <u>125</u> °C 3 @ 260 °C = <u>150</u> °C °C to <u>+125</u> °C	1008 hrs 24 hrs 1008 hrs 1000 cyc
ange: liability Data Si DEVICE NAME : CKAGE : 8mmx9i Test HTOL ELFR PC HTSL TC HAST	ummary: AS0149ATSC00XUE mm iBGA JESD22- AEC Q10 J-STD-020 J JESD22- JESD22- JESD22-	A0-DPBR ation A108 0-008 ESD-A113 A103 A104 A110 A118 0-001	ated with the	Co Ta= <u>125</u> °C Tj, Ta MSL Ta= <u>-55</u> 110°C, 85 110°C, 85	100 % max rated Vcc = <u>125</u> °C 3 @ 260 °C = <u>150</u> °C °C to <u>+125</u> °C % RH, with bias	1008 hrs 24 hrs 1008 hrs 1000 cyc 264 hrs
iability Data S DEVICE NAME : CKAGE : 8mmx90 Test HTOL ELFR PC HTSL TC HAST UHAST	ummary: AS0149ATSC00XUE mm iBGA JESD22- AEC Q10 J-STD-020 J JESD22- JESD22- JESD22- JESD22- AEC Q10	A0-DPBR ation A108 0-008 ESD-A113 A103 A104 A110 A118 0-001 003 lethod 2011	ated with the	Co Ta= <u>125</u> °C Tj, Ta MSL Ta Ta= <u>-55</u> 110°C, 85 110°C, 85 CF	100 % max rated Vcc = <u>125</u> °C 3 @ 260 °C = <u>150</u> °C °C to <u>+125</u> °C % RH, with bias % RH, unbiased	1008 hrs 24 hrs 1008 hrs 1000 cyc 264 hrs
ange: iability Data Si DEVICE NAME : CKAGE : 8mmx90 Test HTOL ELFR PC HTSL TC HAST UHAST WBS	ummary: AS0149ATSC00XUE mm iBGA JESD22- AEC Q10 J-STD-020 J JESD22- JESD22- JESD22- JESD22- JESD22- AEC Q10 AEC Q10 AEC Q MIL-STD883 M	A0-DPBR ation A108 0-008 ESD-A113 A103 A104 A110 A118 00-001 003 Nethod 2011 003	ated with the	Co Ta= <u>125</u> °C Tj, Ta MSL Ta Ta= <u>-55</u> 110°C, 85 110°C, 85 CF CPK >1.67, 0 Fa	100 % max rated Vcc = <u>125</u> °C 3 @ 260 °C = <u>150</u> °C °C to <u>+125</u> °C % RH, with bias % RH, unbiased PK >1.67	1008 hrs 24 hrs 1008 hrs 1000 cyc 264 hrs
ange: iability Data Stress DEVICE NAME : CKAGE : 8mmx90 Test HTOL ELFR PC HTSL TC HAST UHAST WBS WBP	ummary: AS0149ATSC00XUE mm iBGA JESD22- AEC Q10 J-STD-020 J JESD22- JESD22- JESD22- JESD22- JESD22- AEC Q10 AEC Q10 AEC Q10 AEC Q10 AEC Q10 AEC Q10	A0-DPBR ation A108 0-008 ESD-A113 A103 A104 A110 A118 0-001 003 lethod 2011 003 0-002		Co Ta= <u>125</u> °C Tj, Ta MSL Ta Ta= <u>-55</u> 110°C, 85 110°C, 85 CF CPK >1.67, 0 Fail	100 % max rated Vcc = <u>125</u> °C 3 @ 260 °C = <u>150</u> °C °C to <u>+125</u> °C % RH, with bias % RH, unbiased PK >1.67 wils after TC (test #A4)	1008 hrs 24 hrs 1008 hrs 1000 cyc 264 hrs
ange: iability Data Si DEVICE NAME : CKAGE : 8mmx91 Test HTOL ELFR PC HTSL TC HAST UHAST WBS WBP HBM	ummary: AS0149ATSC00XUE mm iBGA JESD22- AEC Q10 J-STD-020 J JESD22- JESD22- JESD22- JESD22- JESD22- JESD22- AEC Q10 AEC Q10 AEC Q10	A0-DPBR ation A108 0-008 ESD-A113 A103 A104 A110 A118 0-001 003 lethod 2011 003 lethod 2011 003 0-002 0-011		Co Ta= <u>125</u> °C Tj, Ta MSL Ta Ta=-55 110°C, 85 110°C, 85 CF CPK >1.67, 0 Fa CPK >1.67, 0 Fail: Fails: 750V for corn	100 % max rated Vcc = <u>125</u> °C 3 @ 260 °C = <u>150</u> °C °C to <u>+125</u> °C % RH, with bias % RH, unbiased PK >1.67 wils after TC (test #A4) s; 2KV HBM	1008 hrs 24 hrs 1008 hrs 1000 cyc 264 hrs



To view attachments:

- 1. Download pdf copy of the PCN to your computer
- 2. Open the downloaded pdf copy of the PCN
- 3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field

4. Then click on the attached file.

Electrical Characteristics Summary:

Electrical characteristics are not impacted. Full electrical performance will be supplied upon FPCN.

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the <u>PCN Customized Portal</u>.

Current Part Number	New Part Number	Qualification Vehicle
AS0149ATSC00XUEA0-DPBR	AS0149ATSC00XUEA1-DPBR	AS0149ATSC00XUEA0-DPBR
AS0149ATSC00XUEA0-TRBR	AS0149ATSC00XUEA1-TRBR	AS0149ATSC00XUEA0-TRBR